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MAGNETRON SPUTTERED YHO THIN FILM OXYDATION DYNAMICS AND OPTICAL PROPERTIES

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THIN FILMS LABORATORY

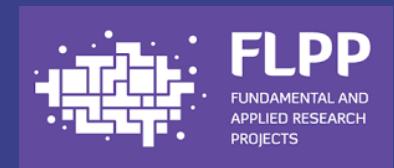


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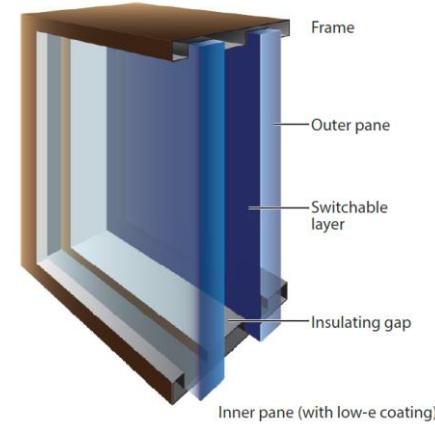
OUTLINE

- Motivation
- Introduction in rare-earth oxyhydrides
- Experimental details
- Results:
 - *In-situ* transmittance measurements
 - X-ray diffraction
 - Electron microscope images
 - Spectroscopic ellipsometry
 - X-ray photoelectron spectroscopy (depth profiling)
- Conclusions

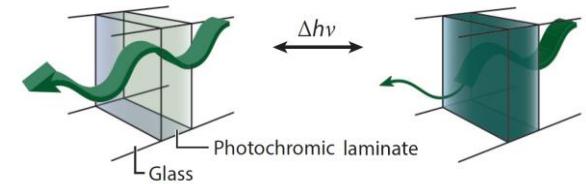
MOTIVATION

- Yttrium and other rare-earth (RE) metal oxy-hydrides (YHO, REHO) are a new class of inorganic **mixed-anion materials** [1]
- They exhibit a **photochromic effect** and a **light-induced resistivity change** at room temperature and ambient pressure [2]
- Photochromic YHO thin films can be prepared by the simply exposing reactively ($\text{Ar}+\text{H}_2$) sputtered metallic $\beta\text{-YH}_2$ films to air [3]. **However, it has not been directly measured when the oxidation mostly occurs - after or during (due to residual oxygen) the deposition of YH_2 films?**
- The aim of this presentation to show the oxidation dynamics of yttrium hydride films during and after deposition process, as well as optical properties.
- Latvian Council of Science FLPP project: **Thin films of rare-earth oxy-hydrides for photochromic applications**

Double-paned insulated glass unit (IGU)



Photochromic



Latvian Council of Science



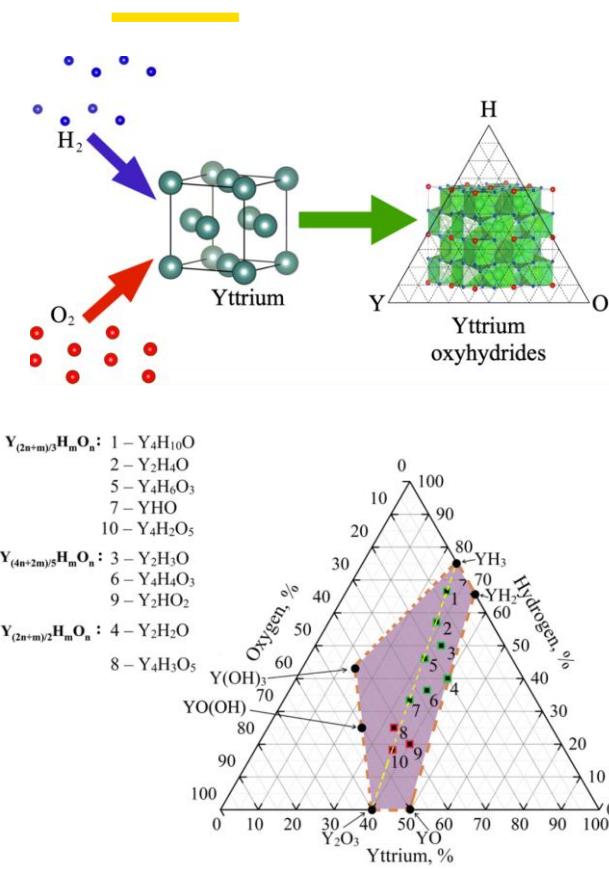
FLPP
FUNDAMENTAL AND
APPLIED RESEARCH
PROJECTS

[1] *Nature communications* 9.1 (2018) 1-15

[2] *Applied Physics Letters* 111 (2017) 103903.

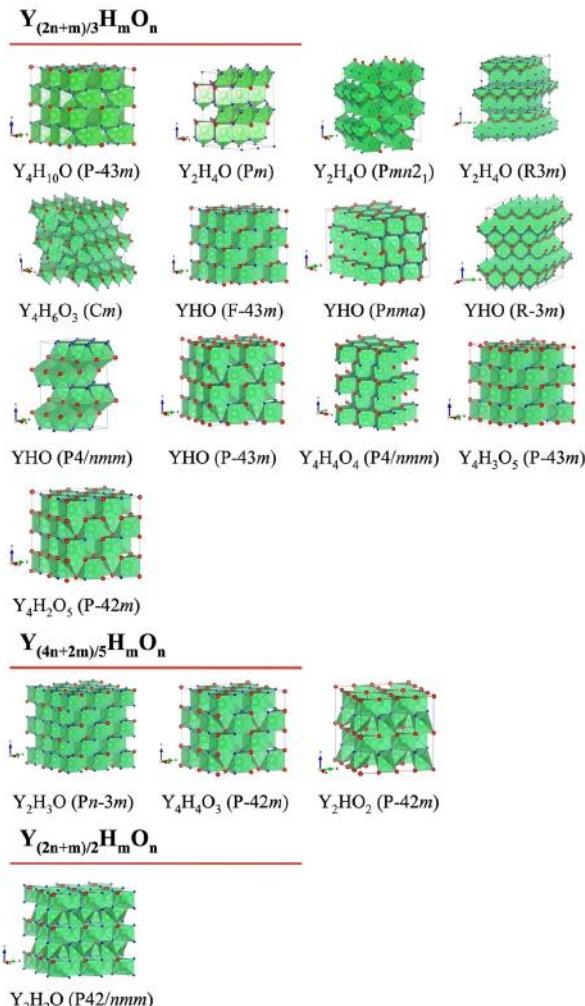
[3] *Sol. Energy Mater. Sol. Cells* 177 (2018) 106

YTTRIUM OXYHYDRIDE

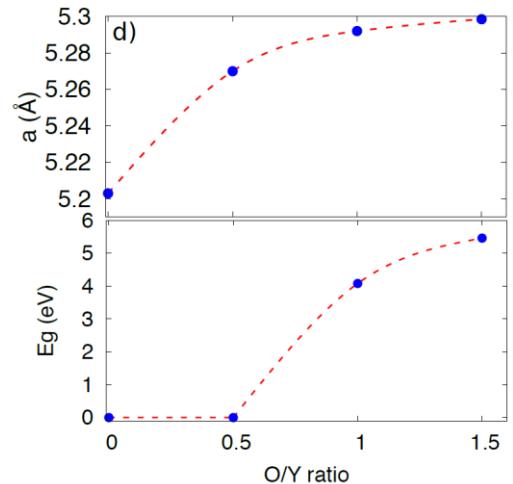
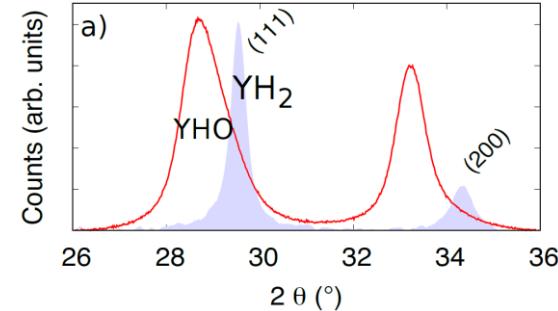


Cryst. Growth Des. 2019, 19, 2574–2582

Physical Review Materials 4.2 (2020): 025201.



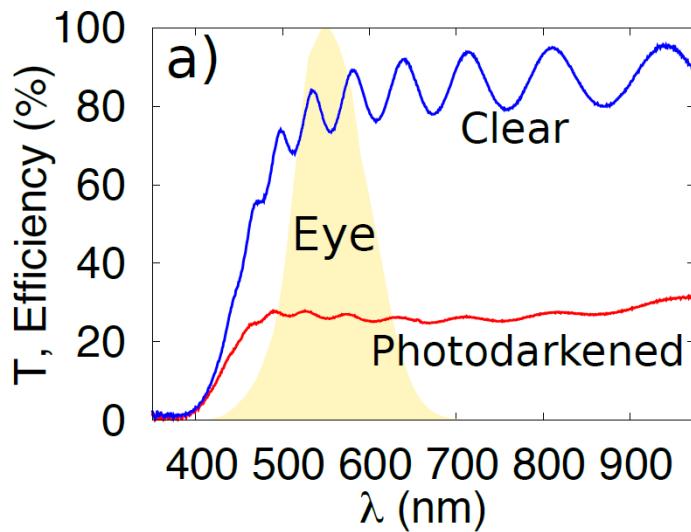
YH_2 fcc Fm-3m



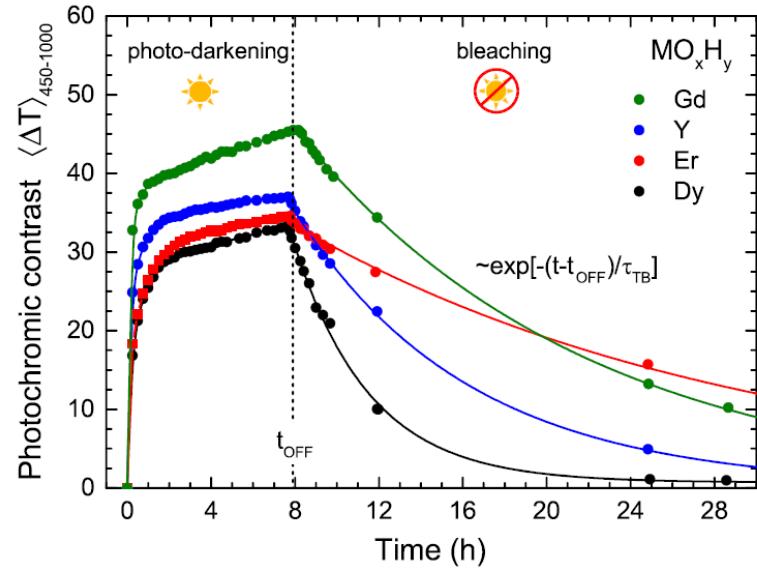
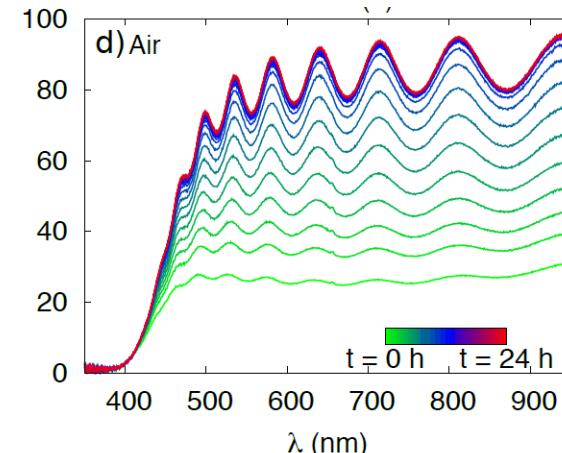
PHOTOCHROMIC EFFECT

—

UV-Blue light irradiation



Physical Review Materials, 4(2), 025201 (2020)



Appl. Phys. Lett. 111, 103903 (2017)

EXPERIMENTAL DETAILS - YHO DEPOSITION

Vacuum coater Sidrabe G500M

Sputtering conditions:

- rectangular magnetron: balanced;
- target:
 - Y (99.95 purity);
 - dimensions 150 mm × 75 mm × 2 mm thick.
- working pressure 3 - 20 mTorr (changed by a throttle valve):
 - Ar flow 30 sccm;
 - H₂ flow 16 sccm.
- constant average power regime (200 W);
- pulsed-DC power supply P-DC-EP05 EnerPulse 5 kW:
 - frequency - 80 kHz;
 - Off time - 2.5 μs;
- spectrometer: CMOS detector, StarLine AvaSpec-ULS2048CL-EVO



YHO deposition:

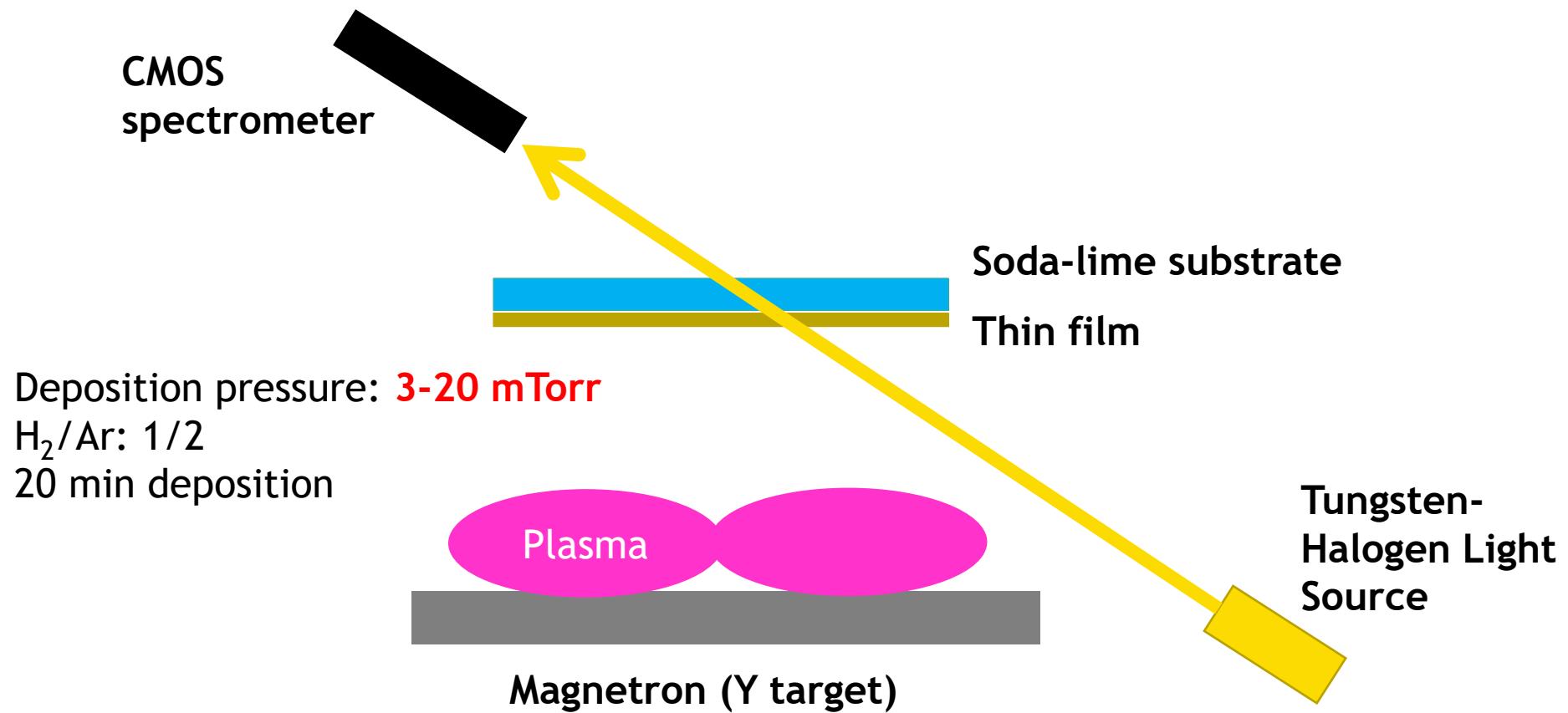
- soda-lime glass and Ti substrates;
- substrate temperature: RT (without intentional heating);
- deposition time: 20 min;
- distance from target to substrate: ≈10 cm (facing the target axis);



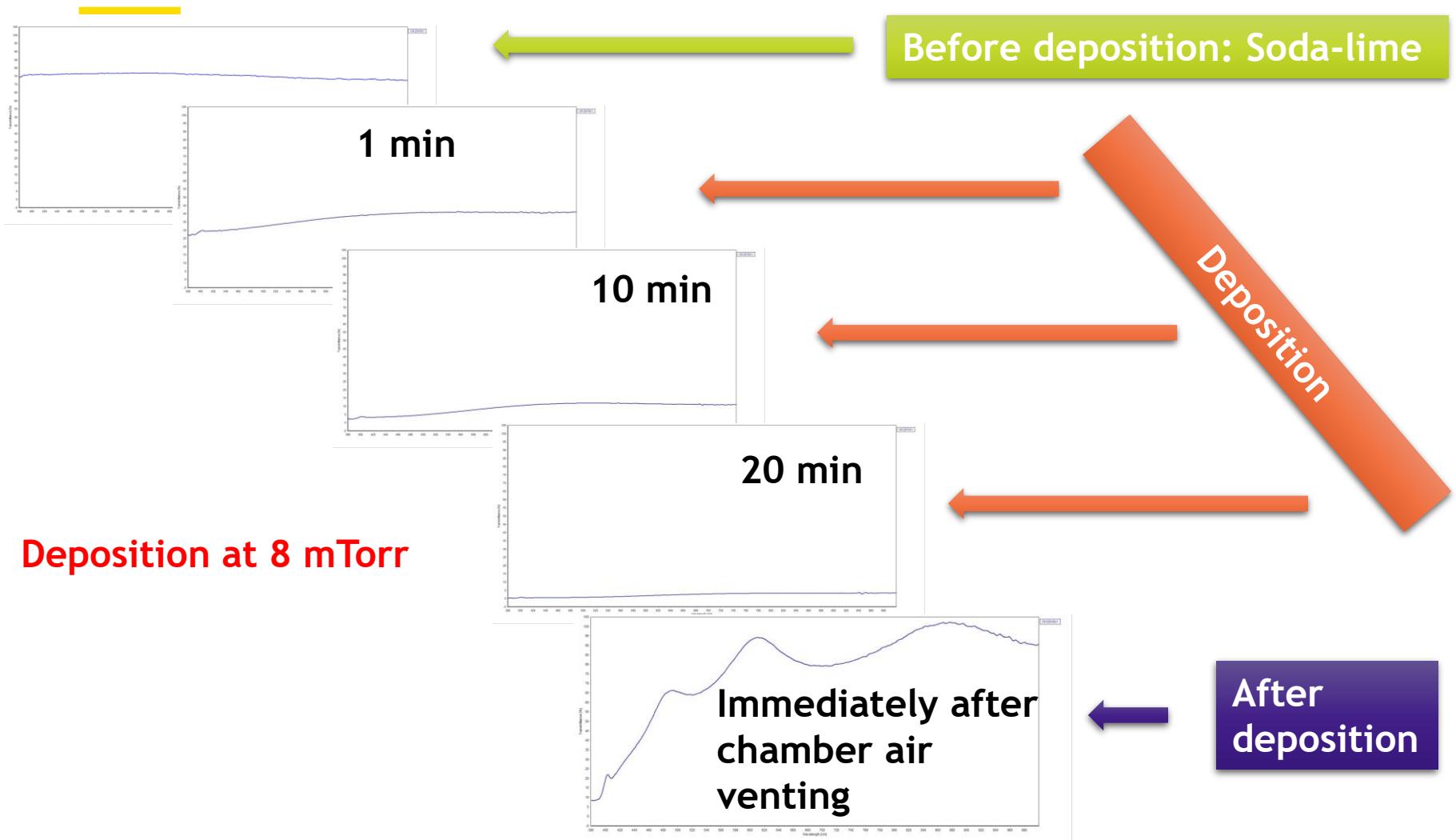
DEPOSITED YHO SAMPLES

Sample No.	Sputtering pressure (mTorr)	Voltage (V)	Thickness (nm)
1	3.0	302	330
2	6.0	299	209
3	6.5	299	305
4	7.0	299	357
5	7.5	297	378
6	8.0	298	428
7	9.0	296	442
8	10.0	299	419
9	12.0	296	398
10	20.0	290	462

IN-SITU TRANSMITTANCE MEASUREMENT SETUP

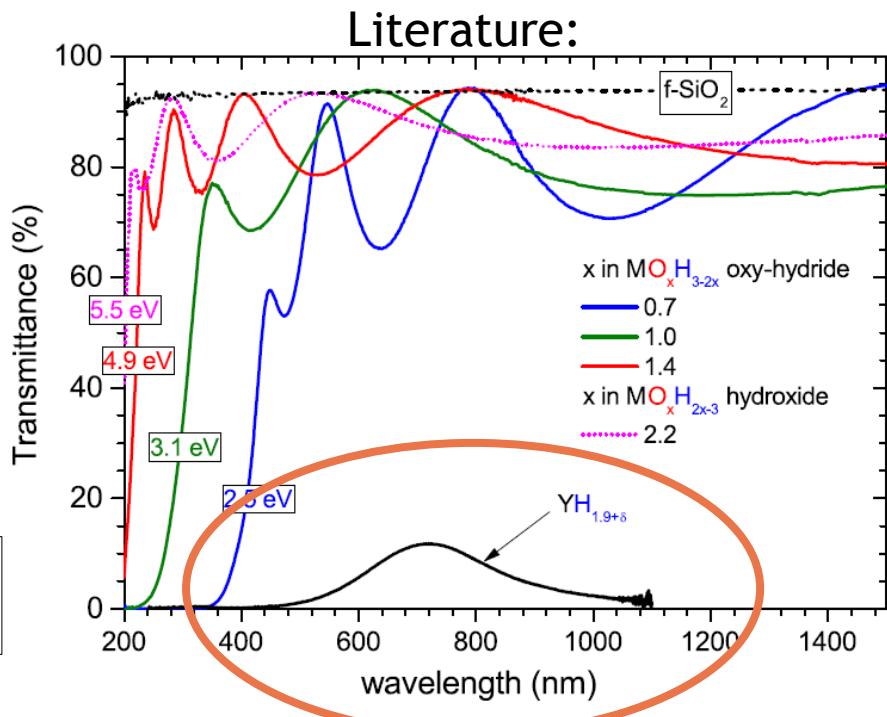
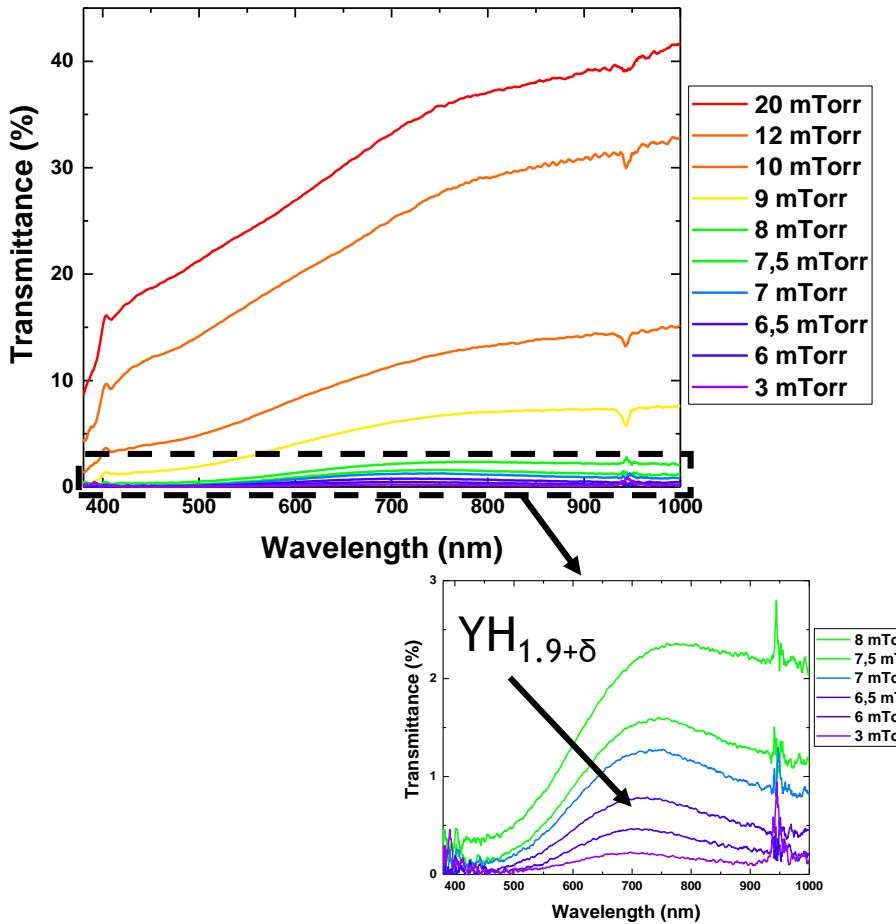


IN-SITU TRANSMITTANCE MEASUREMENT



IN-SITU TRANSMITTANCE

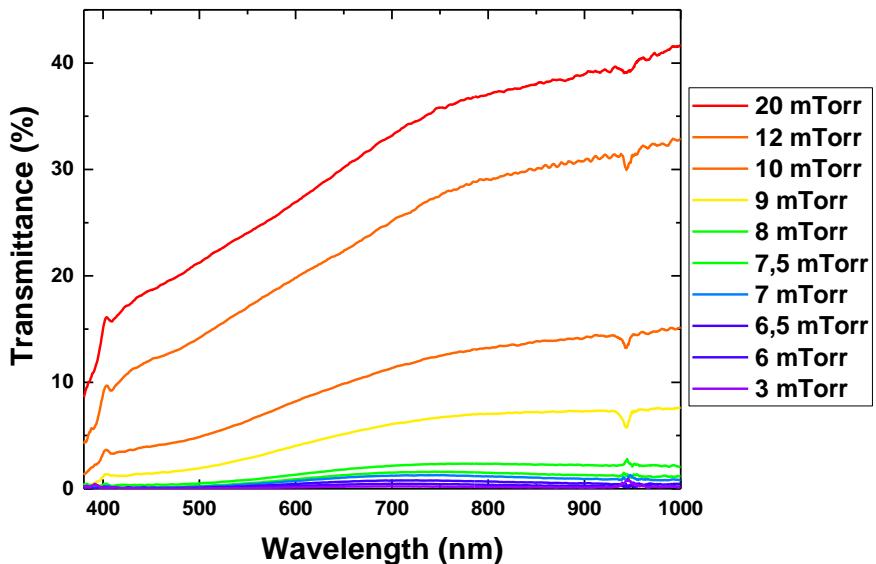
Transmittance spectra of the deposited samples immediately after the deposition.



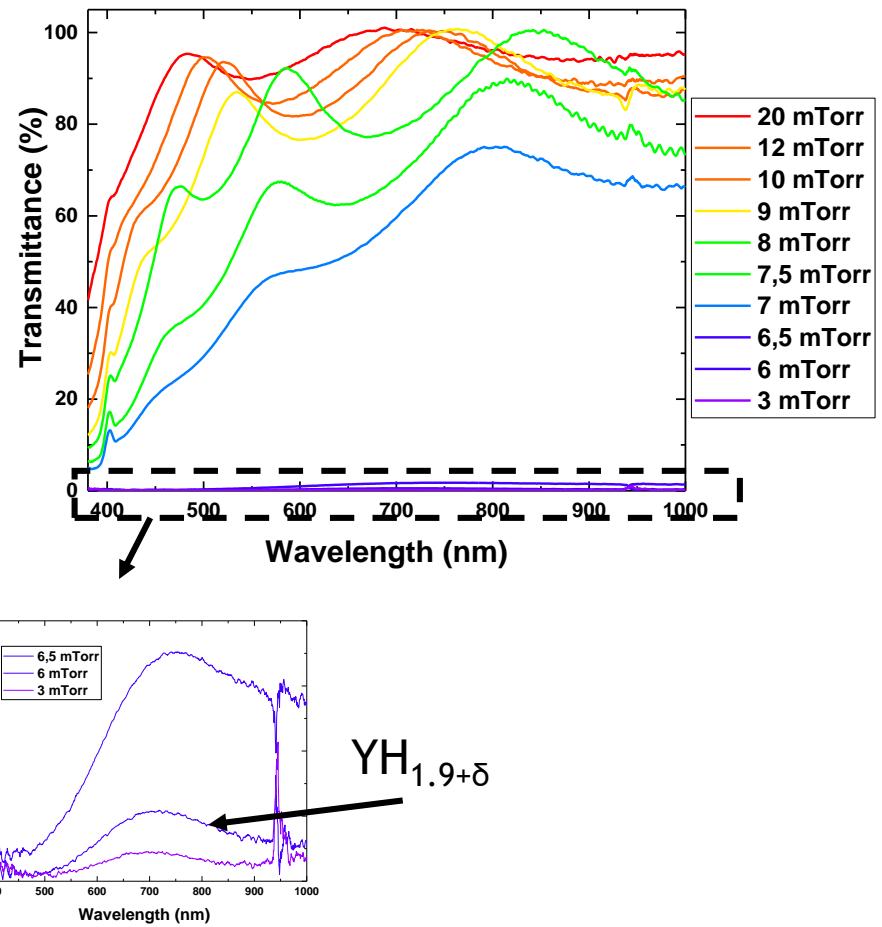
J. Phys. Chem. Lett. 2019, 10, 1342–1348

IN-SITU TRANSMITTANCE

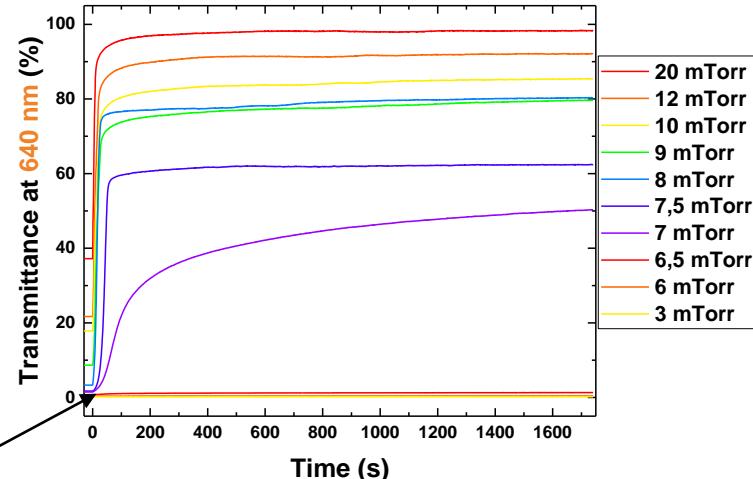
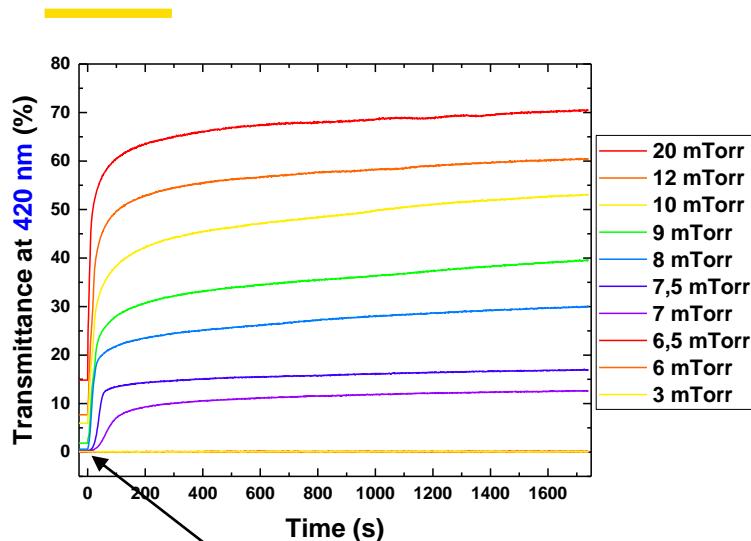
Transmittance spectra of the deposited samples immediately after the deposition.



Transmittance spectra of the deposited samples after 30 min in O₂ (\approx 3 Torr).

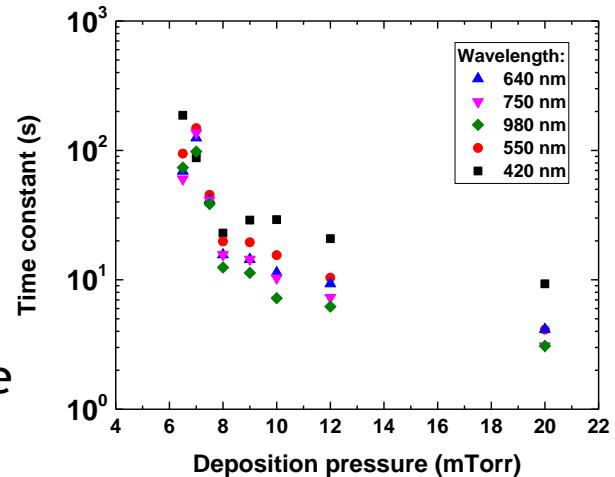


TIME CONSTANT

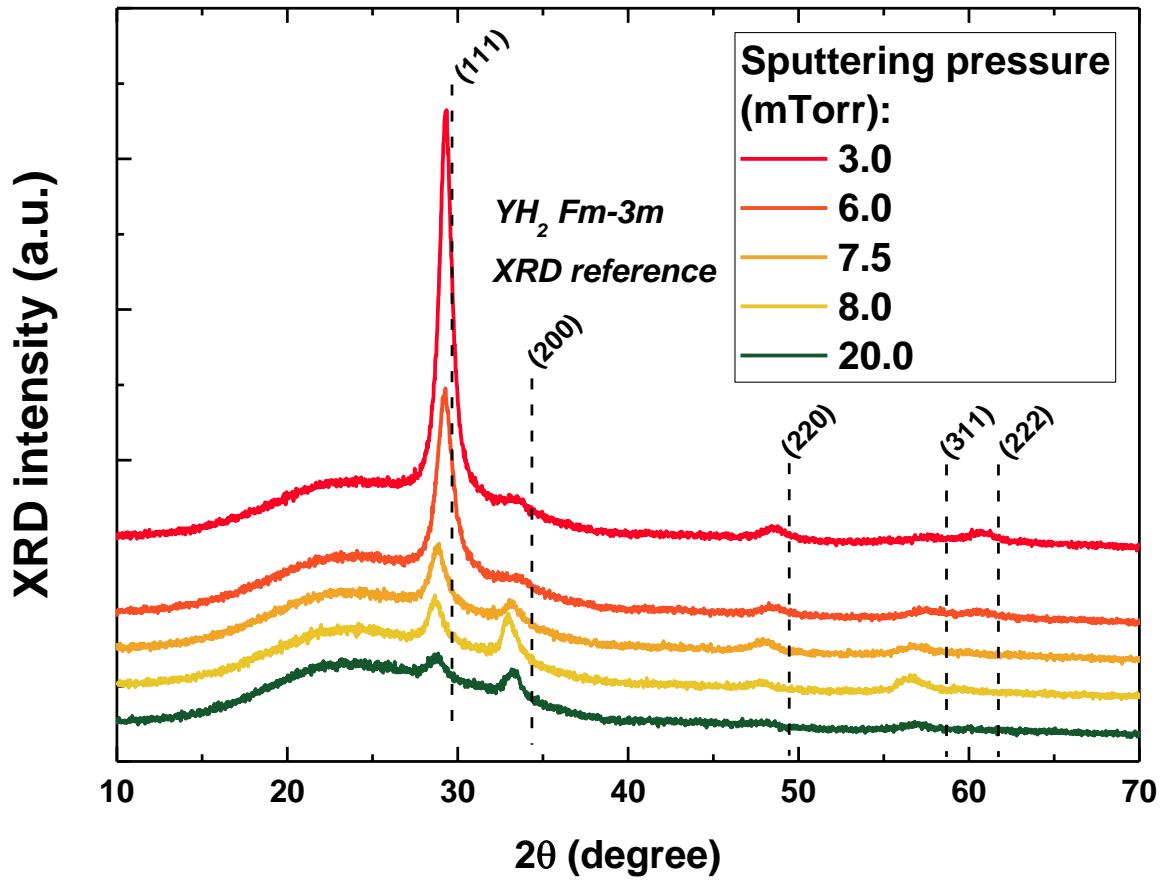


Oxygen inlet
after deposition

Time constant:
Increase in transmittance value
up to 50% of the final value.



XRD OF YHO



SURFACE MORPHOLOGY

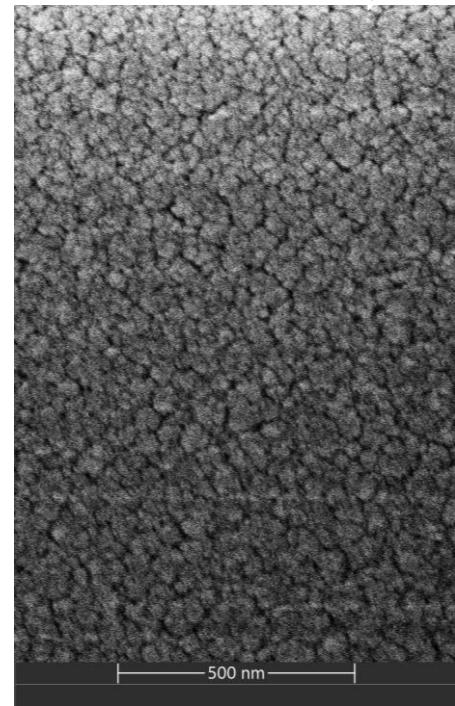
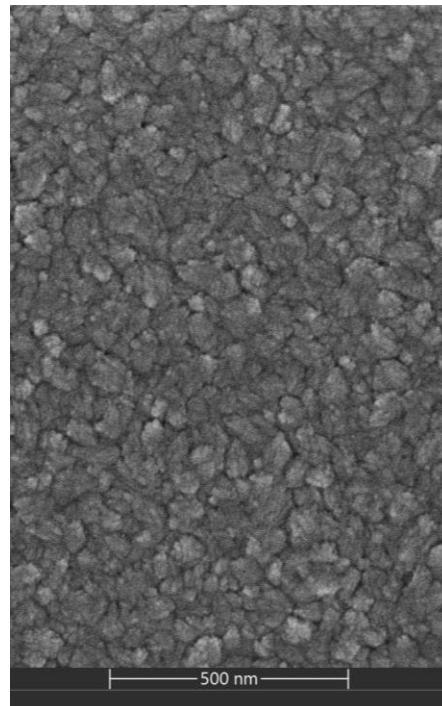
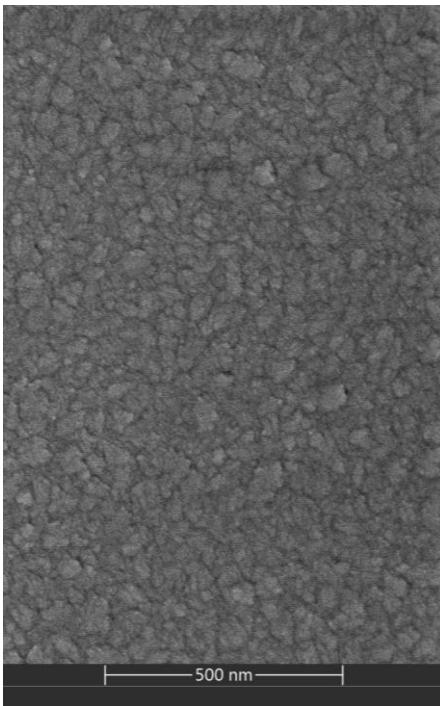
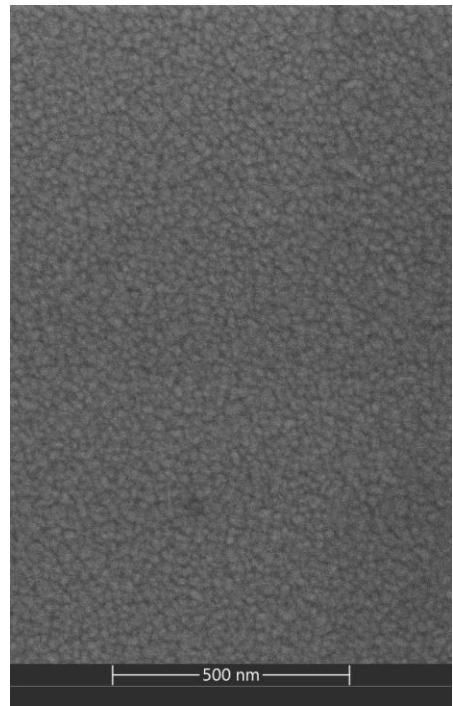
Sputtering pressure

3.0 mTorr

6.5 mTorr

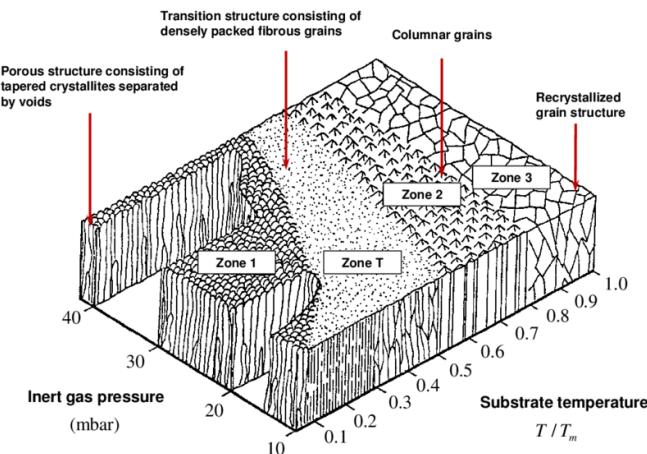
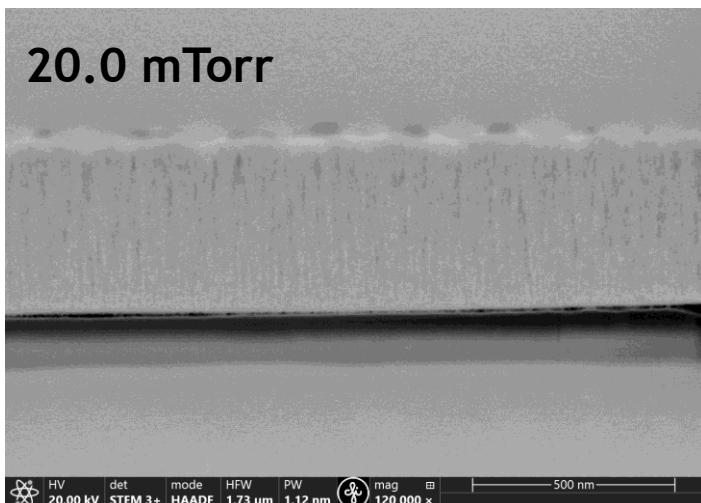
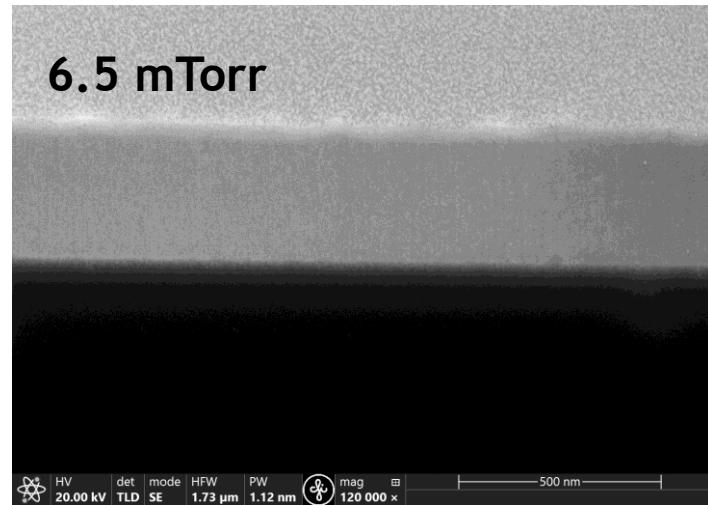
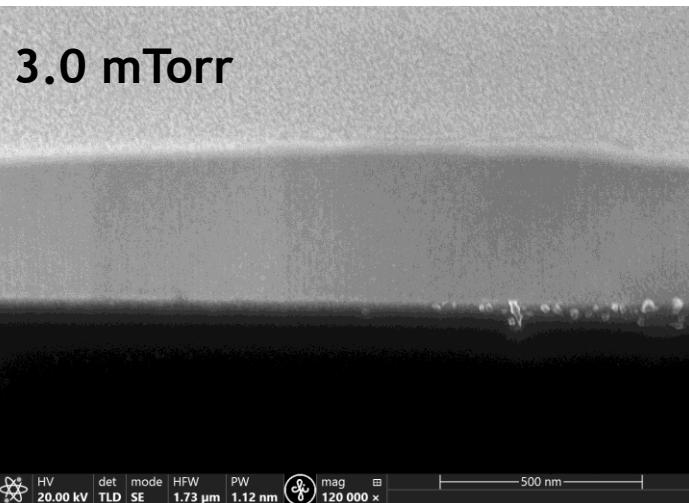
7.5 mTorr

20.0 mTorr



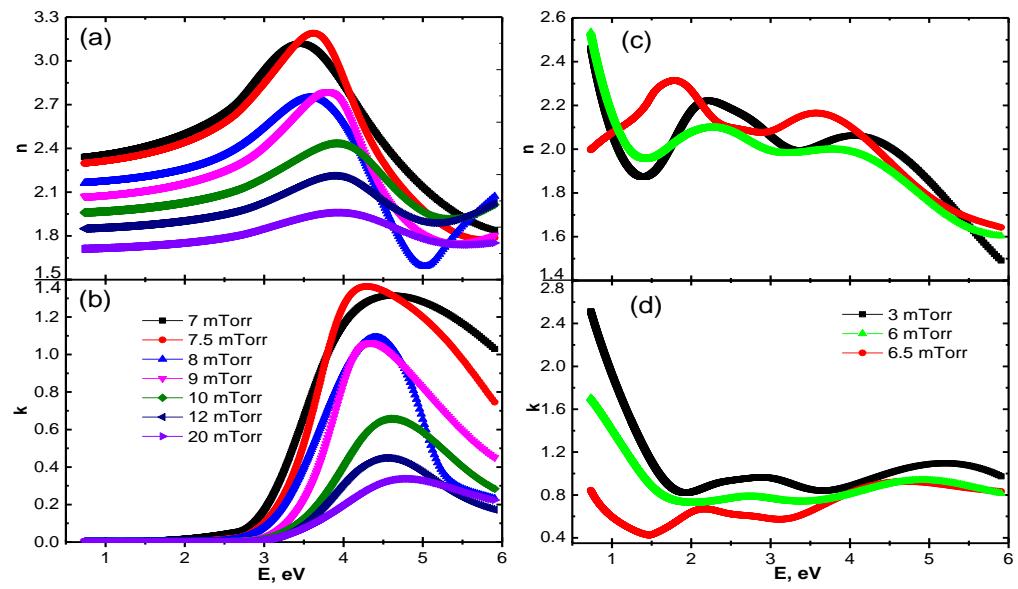
The surface morphology of the films is less dense at higher sputtering pressures.

CROSS-SECTION IMAGES OF YHO FILMS

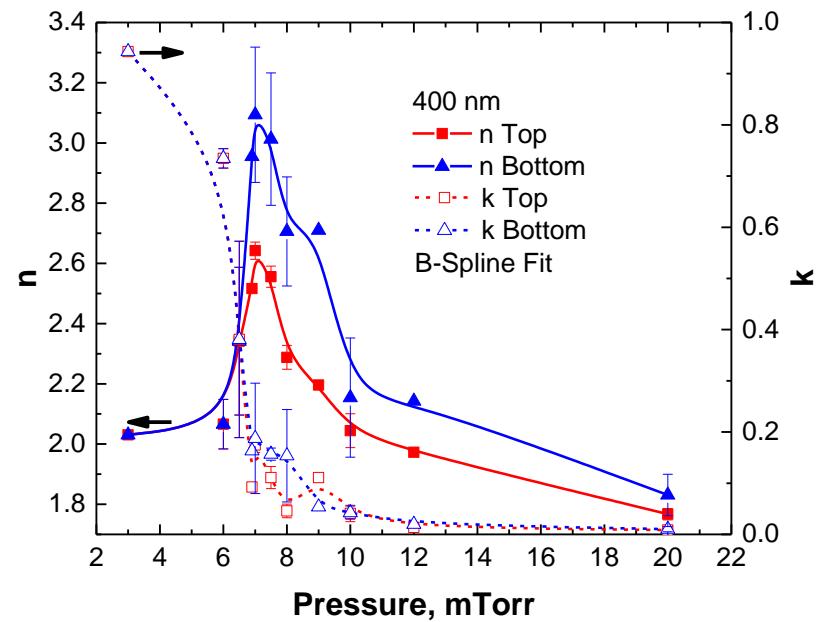


OPTICAL CONSTANTS

The refractive index n (a, c) and extinction coefficient k (b, d) as functions of photon energy and sputtering pressure.

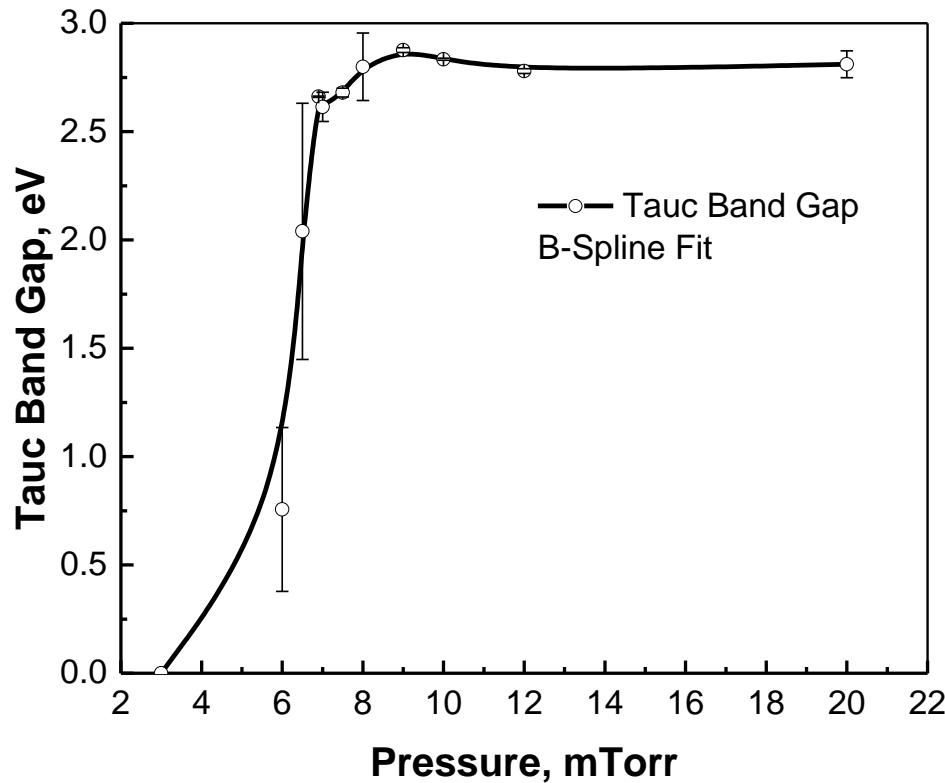


Refractive index n and extinction coefficient k at 400 nm wavelength as functions of sputtering pressure.



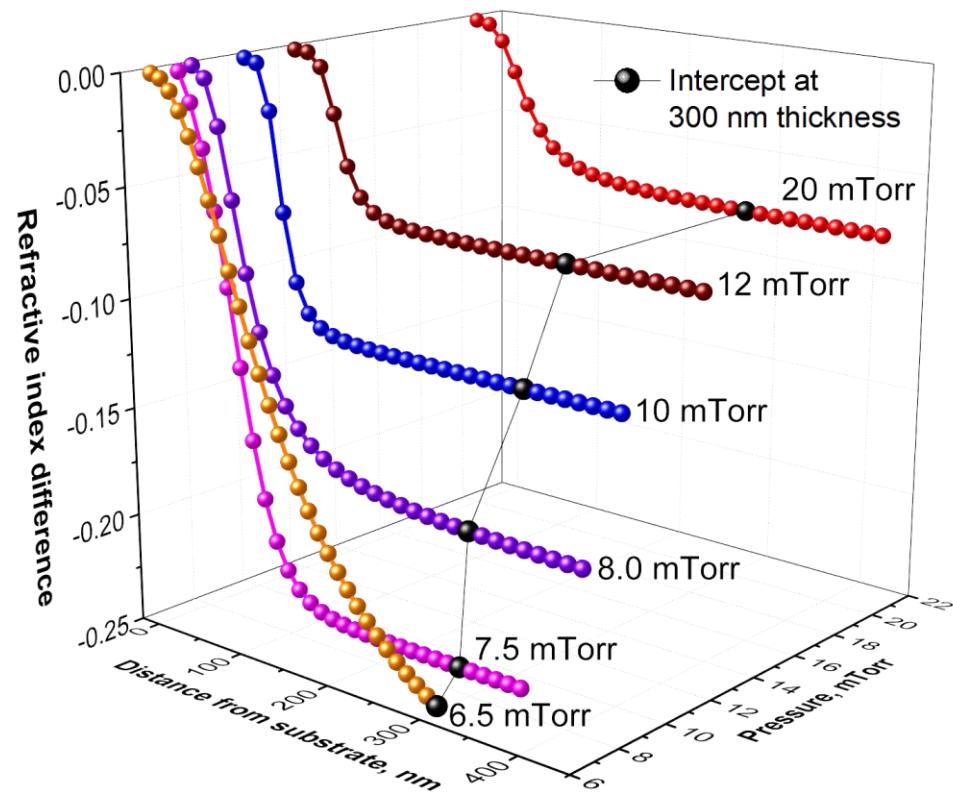
OPTICAL BAND GAP

Tauc band gap E_g (fitting parameter of TLO)
as a function of the sputtering pressure.

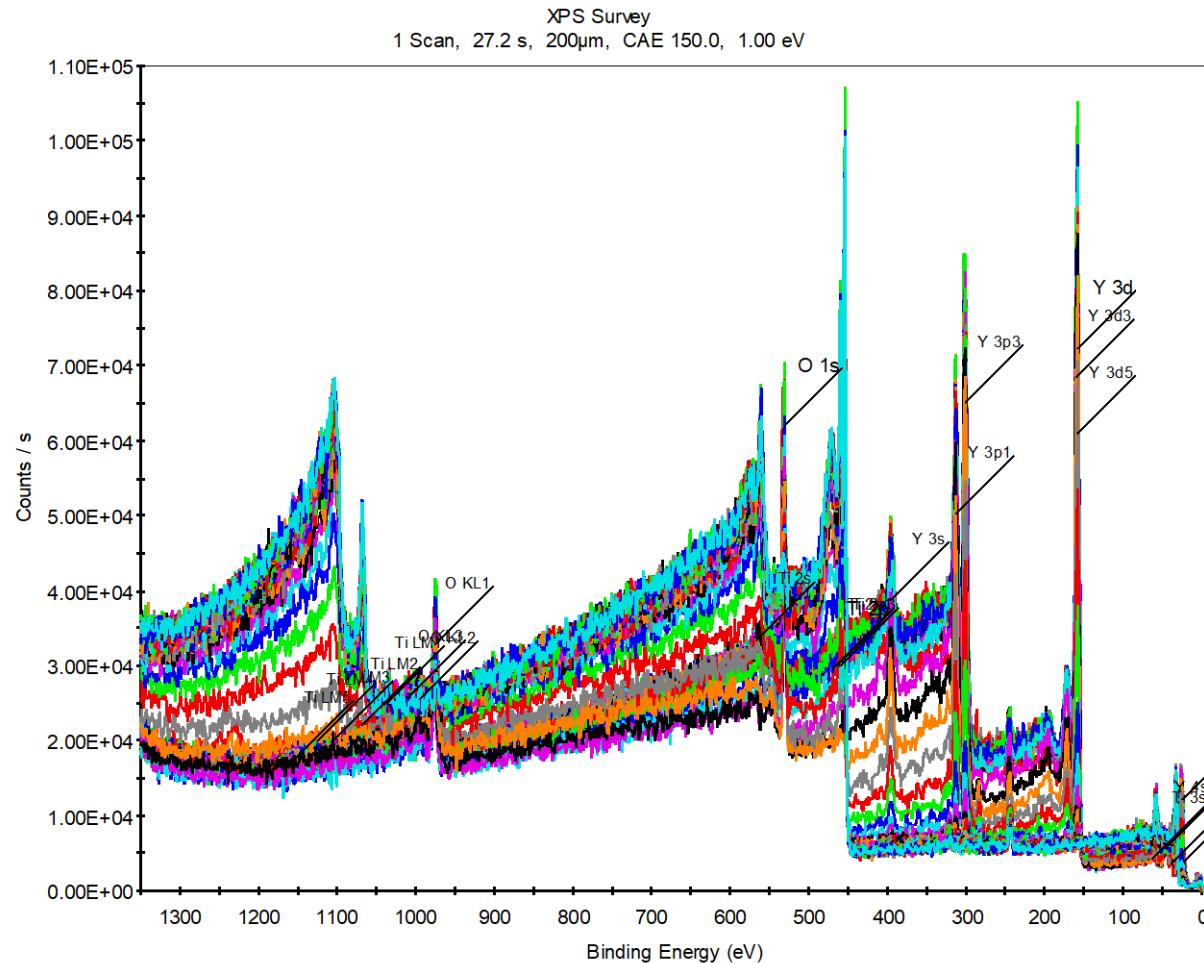


OPTICAL GRADIENT

Optical depth profile (at 1.669 eV or 742.8 nm) of thin films sputtered at different pressures.



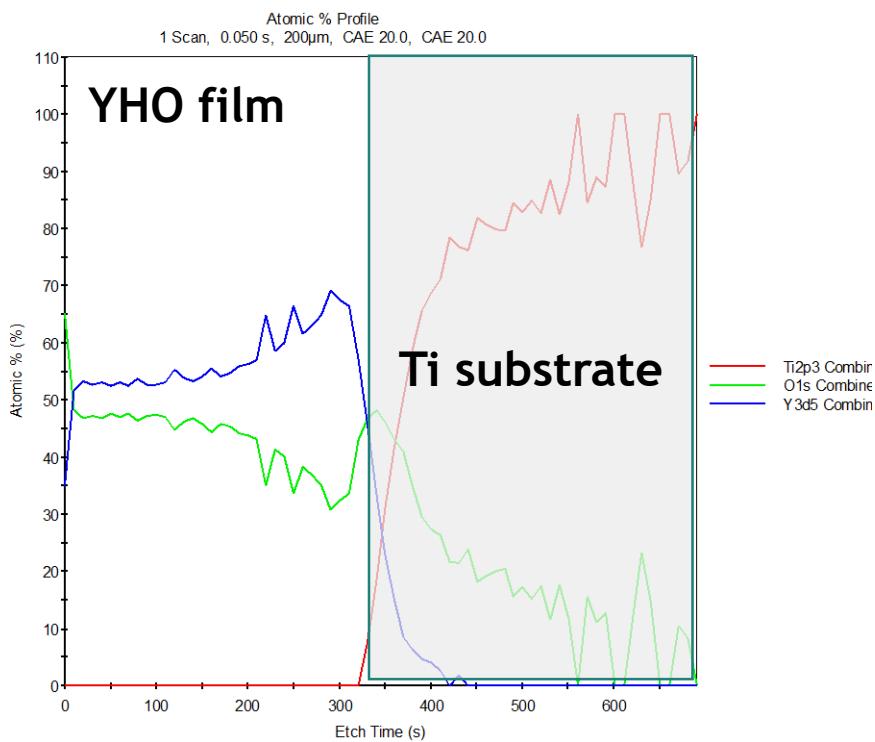
XPS - DEPTH PROFILING



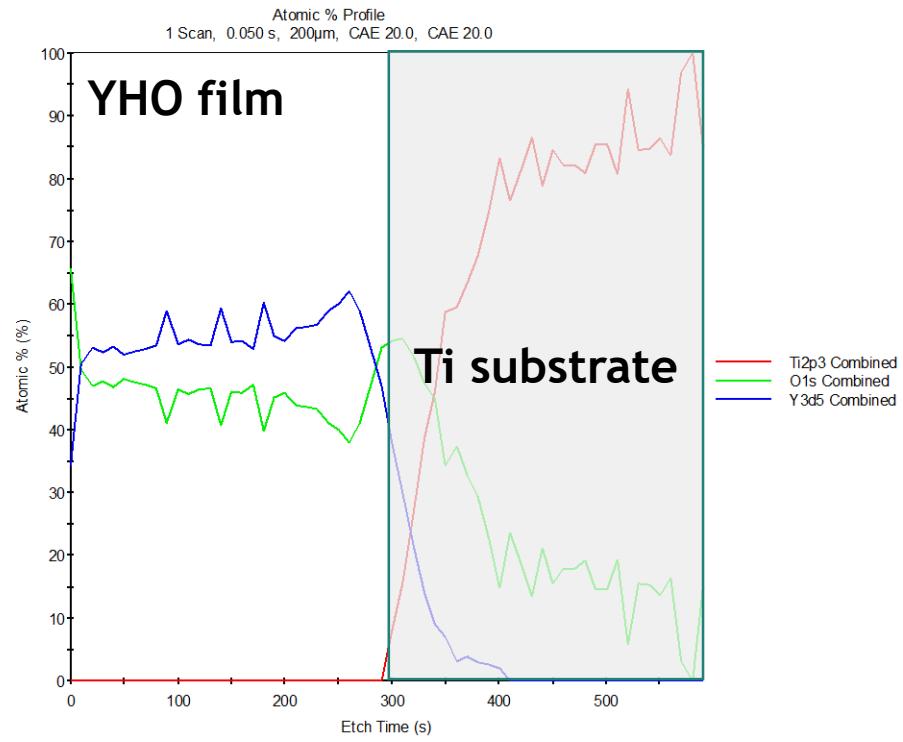
DEPTH PROFILING

YHO films on the Ti substrates

7.0 mTorr



8.0 mTorr



The film composition (O / Y) is not uniform throughout the thickness of the films.

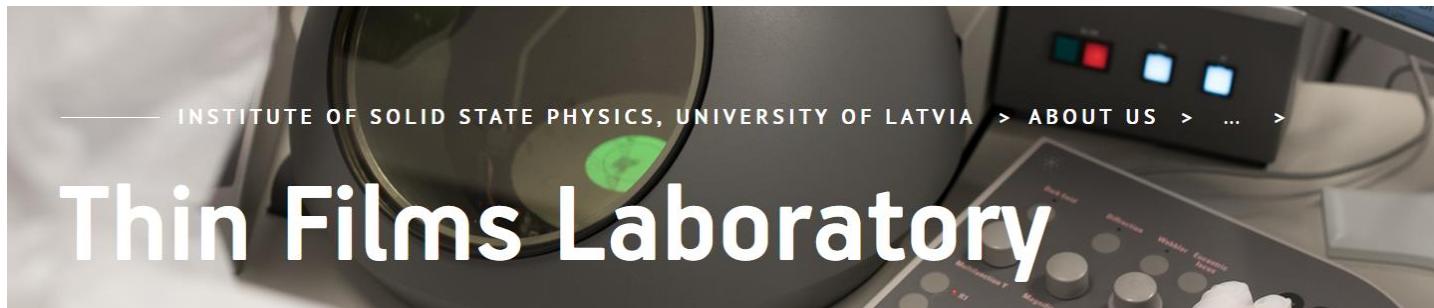


CONCLUSIONS

- The oxidation of YH_{2-x} films during and after deposition occur more rapidly when the higher sputtering pressure is used.
- The most of the oxidation happens when oxygen (or air) is introduced into a vacuum chamber intentionally.
- The lattice of YHO films expands with the deposition pressure due the higher oxygen concentration which is promoted by the less dense structure.
- There is the transition from metallic to semiconducting/insulating YHO films when the deposition pressure is increased (at 7.0 mTorr in our case).
- The transparent films in the visible light range exhibit an optical gradient throughout the thickness of the films due to the nonhomogeneous composition.



Thanks for Your attention !!!



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